- Member of the Texas Instruments Widebus™ Family
- Free-Running CLKA and CLKB Can Be Asynchronous or Coincident
- Read and Write Operations Synchronized to Independent System Clocks
- Two Separate 512 × 18 Clocked FIFOs Buffering Data in Opposite Directions
- IRA and ORA Synchronized to CLKA
- IRB and ORB Synchronized to CLKB

- Microprocessor Interface Control Logic
- Programmable Almost-Full/Almost-Empty Flag
- Fast Access Times of 9 ns With a 50-pF Load and Simultaneous Switching Data Outputs
- Data Rates up to 100 MHz
- Advanced BiCMOS Technology
- Package Options Include 80-Pin Plastic Quad Flatpack (PH) and 80-Pin Thin Plastic Quad Flatpack (PN)





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										(TO	P V	IEV	V)											
		PENA	RSTA	CSA	W/RA	GND	WENA	CLKA	RENA	ORA	Vcc	Vcc	ORB	RENB	CLKB	WENB	GND	W/RB	CSB	RSTB				
Γ	•	80	口 79	口 78	口 77	口 76	 75	口 74	— 73	口 72	— 71	— 70		し 68	□ 67	66	〇 65	— 64	C	ロロ 62 6	1			
AF/AEA] 1	00	10	10		10	10	1 4	10	12	, ,	10	00	00	01	00	00	04	00	02 0		60 🗌	AF/AI	EB
HFA	2																				ł	59 🗌	HFB	
IRA	3 ן																				ł	58 🗌	IRB	
GND	4																				ł	57 [GND	
A0] 5																				ł	56 [B0	
A1	6																				ł	55 🗌	B1	
Vcc] 7																				ł	54 [V _{CC}	
A2	8																				ł	53 [B2	
A3	9																				ł	52 [B3	
GND] 10																				ł	51 [GND	
A4] 11																				ł	50 [B4	
A5] 12																				4	49 🗌	B5	
GND] 13																					48 [GND	
A6	14																					47 [B6	
A7] 15																					46 [
GND] 16																					45 🗌	GND	
A8] 17																						B8	
Г	18																					43 🛛		
Vcc] 19																						V _{CC}	
A10	20																				4	41 ∟	B10	
		21	22	23	24	25	26	27	28	29	30	31	32	33	34	35	36	37	38	39 40	2			
_		A11	GND	A12	A13	Vcc	A14	A15	GND	A16	A17	B17	B16	GND	B15	B14	Vcc	B13	B12	GND	2			

PN PACKAGE

description

A FIFO memory is a storage device that allows data to be written into and read from its array at independent data rates. The SN74ABT7819A is a high-speed, low-power, BiCMOS, bidirectional, clocked FIFO memory. Two independent 512×18 dual-port SRAM FIFOs (FIFOA, FIFOB) on the chip buffer data in opposite directions. Each FIFO has flags to indicate empty and full conditions, a half-full flag, and a programmable almost-full/almost-empty flag.

The SN74ABT7819A is a clocked FIFO, which means each port employs a synchronous interface. All data transfers through a port are gated to the low-to-high transition of a continuous (free-running) port clock by enable signals. The continuous clocks for each port are independent of one another and can be asynchronous or coincident. The enables for each port are arranged to provide a simple bidirectional interface between microprocessors and/or buses with synchronous control.

The state of the A0–A17 outputs is controlled by the port-A chip select (\overline{CSA}) and the port-A write/read select (W/\overline{RA}). When both \overline{CSA} and W/\overline{RA} are low, the outputs are active. The A0–A17 outputs are in the high-impedance state when either \overline{CSA} or W/\overline{RA} is high. Data is written to FIFOA–B from port A on the low-to-high transition of the port-A clock (CLKA) input when \overline{CSA} is low, W/\overline{RA} is high, the port-A write enable (WENA) is high, and the port-A input-ready (IRA) flag is high. Data is read from FIFOB–A to the A0–A17 outputs on the low-to-high transition of CLKA when \overline{CSA} is low, W/\overline{RA} is low, the port-A read enable (RENA) is high, and the port-A output-ready (ORA) flag is high.



description (continued)

The state of the B0–B17 outputs is controlled by the port-B chip select (\overline{CSB}) and the port-B write/read select (W/RB). When both \overline{CSB} and W/RB are low, the outputs are active. The B0–B17 outputs are in the high-impedance state when either \overline{CSB} or W/RB is high. Data is written to FIFOB–A from port B on the low-to-high transition of the port-B clock (CLKB) when \overline{CSB} is low, W/RB is high, the port-B write enable (WENB) is high, and the port-B input-ready (IRB) flag is high. Data is read from FIFOA–B to the B0–B17 outputs on the low-to-high transition of CLKB when \overline{CSB} is low, W/RB is low, the port-B read enable (RENB) is high, and the port-B output-ready (ORB) flag is high.

The setup- and hold-time constraints for the chip selects (\overline{CSA} , \overline{CSB}) and write/read selects (W/\overline{RA} , W/\overline{RB}) enable write and read operations on memory and are not related to the high-impedance control of the data outputs. If a port read enable (RENA or RENB) and write enable (WENA or WENB) are set low during a clock cycle, the chip select and write/read select can switch at any time during the cycle to change the state of the data outputs.

The input-ready (IR) and output-ready (OR) flags of a FIFO are two-stage synchronized to the port clocks for use as reliable control signals. CLKA synchronizes the status of the input-ready flag of FIFOA–B (IRA) and the output-ready flag of FIFOB–A (ORA). CLKB synchronizes the status of the input-ready flag of FIFOB–A (IRB) and the output-ready flag of FIFOA–B (ORB). When the IR flag of a port is low, the FIFO receiving input from the port is full and writes are disabled to its array. When the OR flag of a port is low, the FIFO that outputs data to the port is empty and reads from its memory are disabled. The first word loaded to an empty memory is sent to the FIFO output register at the same time its OR flag is asserted (high). When the memory is read empty and the OR flag is forced low, the last valid data remains on the FIFO outputs until the OR flag is asserted (high) again. In this way, a high on the OR flag indicates new data is present on the FIFO outputs.

The SN74ABT7819A is characterized for operation from 0°C to 70°C.

Function Tables

	PORT A													
	SE	LECT INI	PUTS	A0-A17 PORT-A OPERATION										
CLKA	CSA	W/RA	WENA RENA		A0-A17	PORT-A OPERATION								
Х	Н	Х	Х	Х	High Z	None								
Ŷ	L	н	Н	Х	High Z	Write A0–A17 to FIFOA–B								
Ŷ	L	L	Х	Н	Active	Read FIFOB–A to A0–A17								

				FU	KI D					
	SE		PUTS		B0-B17 PORT-B OPERATION					
CLKB	CSB	W/RB	WENB	RENB	DV-D17	17 PORT-B OPERATION				
Х	Н	Х	Х	Х	High Z	None				
\uparrow	L	н	н	Х	High Z	Write B0–B17 to FIFOB–A				
\uparrow	L	L	Х	Н	Active	Read FIFOA–B to B0–B17				



logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Terminal numbers are for the PH package.



functional block diagram





enable logic diagram (positive logic)



Terminal Functions

TEF	RMINAL [†]	1/0	DESCRIPTION
NAME	NO.	1/0	DESCRIPTION
A0–A17	7, 8, 10, 11, 13, 14, 16, 17, 19, 20, 22, 23, 25, 26, 28, 29, 31, 32	I/O	Port-A data. The 18-bit bidirectional data port for side A.
AF/AEA	3	0	FIFOA–B almost-full/almost-empty flag. Depth offsets can be programmed for AF/AEA or the default value of 128 can be used for both the almost-empty offset (X) and the almost-full offset (Y). AF/AEA is high when X or fewer words or $(512 - Y)$ or more words are stored in FIFOA–B. AF/AEA is forced high when FIFOA–B is reset.
AF/AEB	62	0	FIFOB–A almost-full/almost-empty flag. Depth offsets can be programmed for AF/AEB or the default value of 128 can be used for both the almost-empty offset (X) and the almost-full offset (Y). AF/AEB is high when X or fewer words or $(512 - Y)$ or more words are stored in FIFOB–A. AF/AEB is forced high when FIFOB–A is reset.
B0–B17	58, 57, 55, 54, 52, 51, 49, 48, 46, 45, 43, 42, 40, 39, 37, 36, 34, 33	I/O	Port-B data. The 18-bit bidirectional data port for side B.
CLKA	76	-	Port-A clock. CLKA is a continuous clock that synchronizes all data transfers through port A to its low-to-high transition and can be asynchronous or coincident to CLKB.
CLKB	69	I	Port-B clock. CLKB is a continuous clock that synchronizes all data transfers through port B to its low-to-high transition and can be asynchronous or coincident to CLKA.
CSA	80	I	Port-A chip select. \overline{CSA} must be low to enable a low-to-high transition of CLKA to either write data from A0–A17 to FIFOA–B or read data from FIFOB–A to A0–A17. The A0–A17 outputs are in the high-impedance state when \overline{CSA} is high.
CSB	65	Ι	Port-B chip select. CSB must be low to enable a low-to-high transition of CLKB to either write data from B0–B17 to FIFOB–A or read data from FIFOA–B to B0–B17. The B0–B17 outputs are in the high-impedance state when CSB is high.
[†] Terminal r	numbers are for th	ne PH pa	ickage.



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512 × 18 × 2 CLOCKED BIDIRECTIONAL FIRST-IN, FIRST-OUT MEMORY SCBS756 - MAY 2002

Terminal Functions (Continued)

TERM	/INAL [†]		DESCRIPTION									
NAME	NO.	1/0	DESCRIPTION									
HFA	4	0	FIFOA–B half-full flag. HFA is high when FIFOA–B contains 256 or more words and is low when FIFOA–B contains 255 or fewer words. HFA is set low after FIFOA–B is reset.									
HFB	61	0	FIFOB–A half-full flag. HFB is high when FIFOB–A contains 256 or more words and is low when FIFOB–A contains 255 or fewer words. HFB is set low after FIFOB–A is reset.									
IRA	5	0	Port-A input-ready flag. IRA is synchronized to the low-to-high transition of CLKA. When IRA is low, FIFOA–B is full and writes to its array are disabled. IRA is set low during a FIFOA–B reset and is set high on the second low-to-high transition of CLKA after reset.									
IRB	60	ο	Port-B input-ready flag. IRB is synchronized to the low-to-high transition of CLKB. When IRB is low, FIFOB–A is full and writes to its array are disabled. IRB is set low during a FIFOB–A reset and is set high on the second low-to-high transition of CLKB after reset.									
ORA	74	ο	Port-A output-ready flag. ORA is synchronized to the low-to-high transition of CLKA. When ORA is low, FIFOB–A is empty and reads from its array are disabled. The last valid word remains on the FIFOB–A outputs when ORA is low. Ready data is present for the A0–A17 outputs when ORA is high. ORA is set low during a FIFOB–A reset and goes high on the third low-to-high transition of CLKA after the first word is loaded to an empty FIFOB–A.									
ORB	71	ο	Port-B output-ready flag. ORB is synchronized to the low-to-high transition of CLKB. When ORB is low, FIFOA–B is empty and reads from its array are disabled. The last valid word remains on the FIFOA–B outputs when ORB is low. Ready data is present for the B0–B17 outputs when ORB is high. ORB is set low during a FIFOA–B reset and goes high on the third low-to-high transition of CLKB after the first word is loaded to an empty FIFOA–B.									
PENA	2	I	AF/AEA program enable. After FIFOA–B is reset and before a word is written to its array, the binary value on A0–A7 is latched as an AF/AEA offset when PENA is low and CLKA is high.									
PENB	63	I	AF/AEB program enable. After FIFOB–A is reset and before a word is written to its array, the binary value on B0–B7 is latched as an AF/AEB offset when PENB is low and CLKB is high.									
RENA	75	I	Port-A read enable. A high level on RENA enables data to be read from FIFOB–A on the low-to-high transition of CLKA when CSA is low, W/RA is low, and ORA is high.									
RENB	70	I	Port-B read enable. A high level on RENB enables data to be read from FIFOA–B on the low-to-high transition of CLKB when CSB is low, W/RB is low, and ORB is high.									
RSTA	1	I	FIFOA–B reset. To reset FIFOA–B, four low-to-high transitions of CLKA and four low-to-high transitions of CLKB must occur while RSTA is low. This sets HFA low, IRA low, ORB low, and AF/AEA high.									
RSTB	64	I	FIFOB–A reset. To reset FIFOB–A, four low-to-high transitions of CLKA and four low-to-high transitions of CLKB must occur while RSTB is low. This sets HFB low, IRB low, ORA low, and AF/AEB high.									
WENA	77	I	Port-A write enable. A high level on WENA enables data on A0–A17 to be written into FIFOA–B on the low-to-high transition of CLKA when W/RA is high, CSA is low, and IRA is high.									
WENB	68	I	Port-B write enable. A high level on WENB enables data on B0–B17 to be written into FIFOB–A on the low-to-high transition of CLKB when W/RB is high, CSB is low, and IRB is high.									
W/RA	79	I	Port-A write/read select. A high on W/RA enables A0–A17 data to be written to FIFOA–B on a low-to-high transition of CLKA when WENA is high, \overline{CSA} is low, and IRA is high. A low on W/RA enables data to be read from FIFOB–A on a low-to-high transition of CLKA when RENA is high, \overline{CSA} is low, and ORA is high. The A0–A17 outputs are in the high-impedance state when W/RA is high.									
W/RB	66	I	Port-B write/read select. A high on W/RB enables B0–B17 data to be written to FIFOB–A on a low-to-high transition of CLKB when WENB is high, CSB is low, and IRB is high. A low on W/RB enables data to be read from FIFOA–B on a low-to-high transition of CLKB when RENB is high, CSB is low, and ORB is high. The B0–B17 outputs are in the high-impedance state when W/RB is high.									

[†] Terminal numbers are for the PH package.





NOTE: FIFOB-A is reset in the same manner.

Figure 1. Reset Cycle for FIFOA-B



[†]Written to FIFOA-B

Figure 2. Write Timing – Port A



SN74ABT7819A $512 \times 18 \times 2$

CLOCKED BIDIRECTIONAL FIRST-IN, FIRST-OUT MEMORY SCBS756 - MAY 2002





[†]Written to FIFOB–A

Figure 3. Write Timing – Port B





NOTE: Operation of FIFOB-A is identical to that of FIFOA-B.

Figure 4. ORB-Flag Timing and First Data-Word Fall Through When FIFOA-B Is Empty





NOTE: Operation of FIFOB-A is identical to that of FIFOA-B.





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‡Read from FIFOA-B







SN74ABT7819A

СЛ

|2 |×

18×

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offset values for AF/AE

The AF/AE flag of each FIFO has two programmable limits: the almost-empty offset value (X) and the almost-full offset value (Y). They can be programmed from the input of the FIFO after it is reset and before a word is written to its memory. An AF/AE flag is high when its FIFO contains X or fewer words or (512 - Y) or more words.

To program the offset values for AF/AEA, PENA is brought low after FIFOA–B is reset and only when CLKA is low. On the following low-to-high transition of CLKA, the binary value on A0–A7 is stored as the almost-empty offset value (X) and the almost-full offset value (Y). Holding PENA low for another low-to-high transition of CLKA reprograms Y to the binary value on A0–A7 at the time of the second CLKA low-to-high transition.

During the first two CLKA cycles used for offset programming, \overline{PENA} can be brought high only when CLKA is low. \overline{PENA} can be brought high at any time after the second CLKA pulse used for offset programming returns low. A maximum value of 255 can be programmed for either X or Y (see Figure 9). To use the default values of X = Y = 128, \overline{PENA} must be tied high. No data is stored in FIFOA–B while the AF/AEA offsets are programmed. The AF/AEB flag is programmed in the same manner, with \overline{PENB} enabling CLKB to program the offset values taken from B0–B7.



Figure 9. Programming X and Y Separately for AF/AEA



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51–7.

recommended operating conditions

		MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	V
VIH	High-level input voltage	2			V
VIL	Low-level input voltage			0.8	V
VI	Input voltage	0		VCC	V
ЮН	High-level output current			-12	mA
IOL	Low-level output current			24	mA
$\Delta t/\Delta v$	Input transition rise or fall rate			5	ns/V
TA	Operating free-air temperature	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TE	ST CONDITIONS	MIN T	YP‡ MAX	UNIT		
VIK		V _{CC} = 4.5 V,	I _I = -18 mA		-1.2	V		
		V _{CC} = 4.5 V,	I _{OH} = –3 mA	2.5				
VOH		V _{CC} = 5 V,	I _{OH} = –3 mA	3		V		
		V _{CC} = 4.5 V,	I _{OH} = -12 mA	2				
VOL		V _{CC} = 4.5 V,	I _{OL} = 24 mA		0.5	V		
Ц		V _{CC} = 5.5 V,	$V_I = V_{CC}$ or GND		±1	μA		
Iozh§		V _{CC} = 5.5 V,	V _O = 2.7 V		50	μA		
Iozl§		V _{CC} = 5.5 V,	$V_{O} = 0.5 V$		-50	μA		
۱0¶		V _{CC} = 5.5 V,	V _O = 2.5 V	-40 -	100 –180	mA		
			Outputs high		15			
ICC		$V_{CC} = 5.5 \text{ V}, I_{O} = 0,$ $V_{I} = V_{CC} \text{ or GND}$	Outputs low		95			
			Outputs disabled		15			
Ci	Control inputs	VI = 2.5 V or 0.5 V			12	pF		
Cio	A or B ports	V _O = 2.5 V or 0.5 V			14	pF		

[‡] All typical values are at $V_{CC} = 5 V$, $T_A = 25^{\circ}C$.

\$ The parameters IOZH and IOZL include the input leakage current.

I Not more than one output should be tested at a time, and the duration of the test should not exceed one second.



timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 10)

			'7819	A-10	'7819	A-12	'7819	A-15	'7819	A-20	'7819	A-30	UNIT
			MIN	MAX	UNIT								
fclock	Clock freq	uency		100		80		67		50		33.3	MHz
t _W	Pulse duration	CLKA, CLKB high or low	4.5		4.5		6		8		11		ns
		A0–A17 before CLKA↑ and B0–B17 before CLKB↑	2		3		4		5		5		
	CSA before CLKA↑ and CSB before CLKB↑	6		6		6		7		7			
		W/RA before CLKA↑ and W/RB before CLKB↑	6		6		6		7		7		
^t su	Setup time	WENA before CLKA↑ and WENB before CLKB↑	4		4		4		5		5		ns
	RENA before CLKA [↑] and RENB before CLKB [↑]	5		5		5		5		6			
		PENA before CLKA↑ and PENB before CLKB↑	3		3		4		5		5		
		RSTA or RSTB low before first CLKA↑ and CLKB↑†	3		3		4		5		5		
		A0–A17 after CLKA↑ and B0–B17 after CLKB↑	0		0		0		0		0		
		CSA after CLKA↑ and CSB after CLKB↑	0		0		0		0		0		
		W/RA after CLKA↑ and W/RB after CLKB↑	0		0		0		0		0		
^t h	Hold time	WENA after CLKA↑ and WENB after CLKB↑	0		0		0		0		0		ns
	RENA after CLKA↑ and RENB after CLKB↑	0		0		0		0		0			
	PENA after CLKA low and PENB after CLKB low	2		2		2		2		2			
		RSTA or RSTB low after fourth CLKA↑ and CLKB↑†	3		3		3		4		4		

[†] To permit the clock pulse to be utilized for reset purposes



 $\begin{array}{c} \text{SN74ABT7819A} \\ 512 \times 18 \times 2 \\ \text{CLOCKED BIDIRECTIONAL FIRST-IN, FIRST-OUT MEMORY} \end{array}$

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switching characteristics over recommended ranges of supply voltage and operating free-air temperature, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 10)

	FROM	то	'7	7819A-1	0	'7819	A-12	'7819	A-15	'7819	A-20	'7819		
PARAMETER	(INPUT)	(OUTPUT)	MIN	түр†	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
f _{max}	CLKA or CLKB		100			80		67		50		33.3		MHz
.	CLKA↑	A0–A17	3	6	8	4	9	4	10	4	12	4	14	ns
^t pd	CLKB↑	B0–B17	3	6	8	4	9	4	10	4	12	4	14	115
• .†	CLKA↑	A0–A17		5										
tpd‡	CLKB↑	B0–B17		5										ns
	CLKA↑	IRA	4		9	4	9	4	10	4	12	4	14	
	CLKB↑	IRB	4		9	4	9	4	10	4	12	4	14	
4.	CLKA 1	ORA	3.5		9	3.5	9	3.5	10	3.5	12	3.5	14	
^t pd	CLKB↑	ORB	3.5		9	3.5	9	3.5	10	3.5	12	3.5	14	ns
	CLKA↑	AF/AEA	8		17	8	17	8	17	8	18	8	20	
	CLKB↑	AF/AEA	8		17	8	17	8	17	8	18	8	20	
^t PLH	RSTA	AF/AEA	4		12	4	12	4	14	4	15	4	16	ns
^t pd	CLKA↑		8		17	8	17	8	17	8	18	8	20	
	CLKB↑	AF/AEB	8		17	8	17	8	17	8	18	8	20	ns
	RSTB	AF/AEB	4		12	4	12	4	14	4	15	4	16	
^t PLH	CLKA↑	HFA	8		17	8	17	8	17	8	18	8	20	
	CLKB↑		8		17	8	17	8	17	8	18	8	20	ns
^t PHL	RSTA	HFA	4		12	4	12	4	14	4	15	4	16	
	CLKA↑	HFB	8		17	8	17	8	17	8	18	8	20	
^t PLH	CLKB↑		8		17	8	17	8	17	8	18	8	20	
^t PHL	RSTB	HFB	4		12	4	12	4	14	4	15	4	16	ns
	CSA	AO A47	2.5		8	2.5	8	2.5	9	2.5	10	2.5	11	
	W/RA	A0–A17	2.5		8	2.5	8	2.5	9	2.5	10	2.5	11	
ten	CSB		2.5		8	2.5	8	2.5	9	2.5	10	2.5	11	ns
	W/RB	B0–B17	2.5		8	2.5	8	2.5	9	2.5	10	2.5	11	
	CSA	AO A47	2.5		8	2.5	8	2.5	9	2.5	10	2.5	11	
4	W/RA	A0–A17	2.5		8	2.5	8	2.5	9	2.5	10	2.5	11	1
^t dis	CSB	D0 D17	2.5		8	2.5	8	2.5	9	2.5	10	2.5	11	ns
	W/RB	B0–B17	2.5		8	2.5	8	2.5	9	2.5	10	2.5	11	

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

[‡] This parameter is measured with a 30-pF load (see Figure 11).





PARAMETER MEASUREMENT INFORMATION

Figure 10. Load Circuit and Voltage Waveforms



TYPICAL CHARACTERISTICS



Figure 11



Figure 12



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Mailing Address:

Texas Instruments Post Office Box 655303 Dallas, Texas 75265

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